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A A	Au layer is not required in preparing the mask	
On	e can completely avoid mask underetching effects	© All Rights Re
e polytechn The red tradema	nique fédérale de Lausanne. All rights reserved except where noted, edX, Open edX and their respective logos a e etching rate is significantly enhanced, yielding a higher throughput arks of edX inc.	re OPEN ed
of Service 8	<u>&amp; Honor Code</u> <u>Privacy Policy</u> e Cr layer is not required for depositing the photoresist mask on the Pyrex substrate	
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oroduces very stror need for t	ion $e$ of 40 wt% NH <sub>4</sub> F with 49 wt% HF is called buffered oxide etch or buffered HF (BHF). The sa slower and less aggressive etch so that photoresist masks can be used. Photoresist wingly degraded in pure(=49%) HF baths. In a Pyrex etching process in a BHF solution, there the deposition of an expensive Au mask, as photoresist can be maintained in the BHF backsion and glass wet etching" video from 5:05 to 10:45 for detailed explanations.	ould be e is no
2. What is	s a commonly used application of HF etching?	
О То	make the wafer surface more hydrophilic	
Ото	remove the residual organics from the wafer surface	
Ото	thermally stabilize the structures on the wafer	
Ото	form free standing structures	
	of etching is used for locally removing a ${ m SiO_2}$ layer to define free-standing structures like tuators. See "HF bath for SiO2 and glass wet etching" video from 0:10 to 1:20 for detailed	
Submit	t	
<b>1</b> Answ	wers are displayed within the problem	